

**Search Notes**

Application/Control No.

10/731,698

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under  
Reexamination

CLARK, DAVID L.

Art Unit

1745

**SEARCHED**

Class	Subclass	Date	Examiner
429	34	4/16/2007	DWY
429	38	4/16/2007	DWY
429	39	4/16/2007	DWY

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
429	34	4/16/2007	DWY
429	38	4/16/2007	DWY
429	39	4/16/2007	DWY

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	4/16/2007	DWY
Inventorship Search	4/16/2007	DWY